

Bayesian Data Analytics for Reliability Modeling Improvement

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DSSI Laboratory



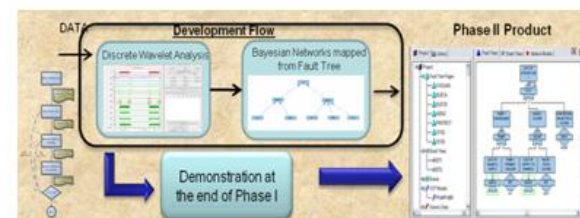
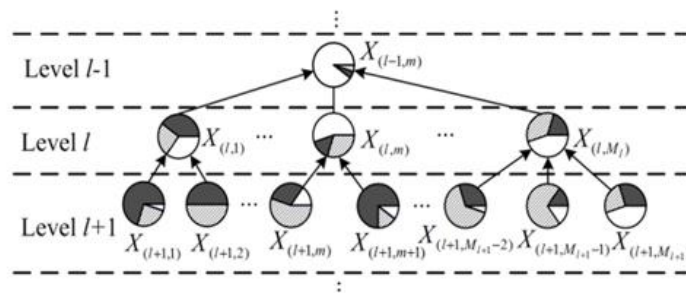
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Some of Current and Former Team Members in DSSI Lab at Dept. of IMSE:

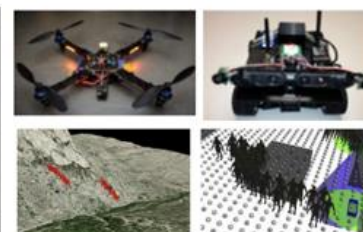
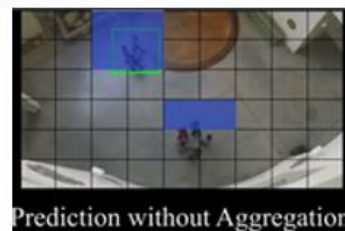
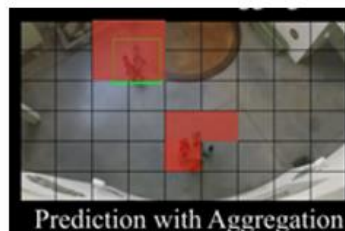


Research Expertise and Highlights:

- Multi-level Data Integration and Analytics for Mission Critical System Reliability Assessment, Testing, Diagnosis, Prognosis and Real-Time Health Management.



- Multi-fidelity Data Integration and Analytics for Crowd Surveillance Improvement.



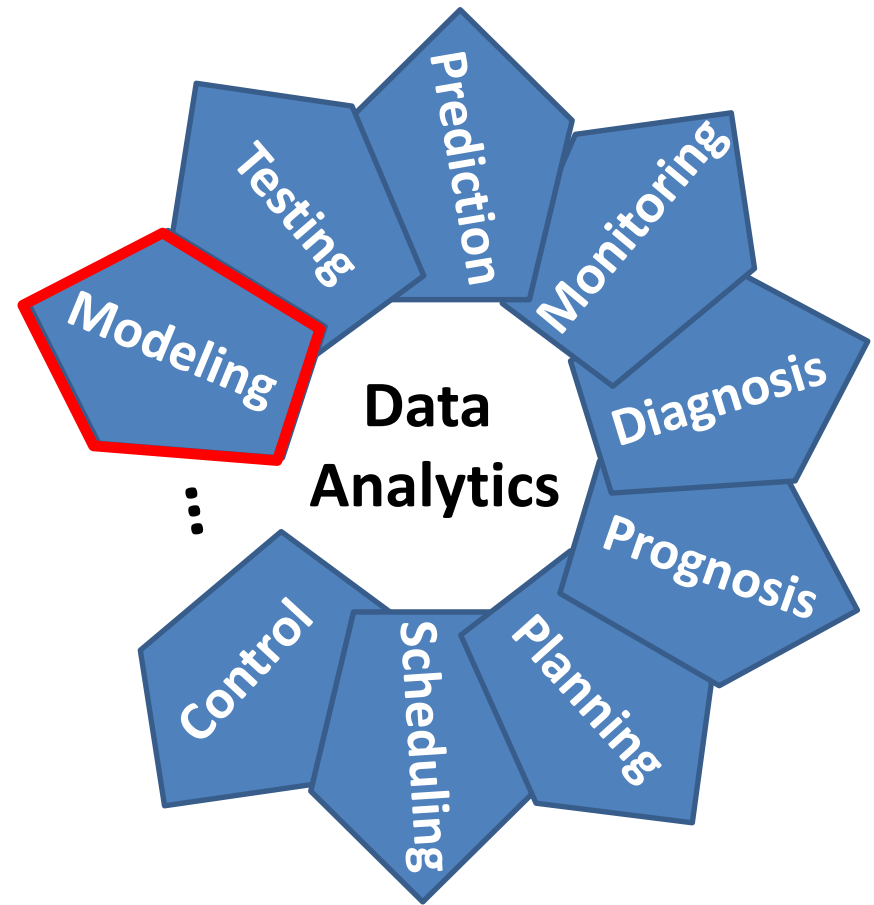
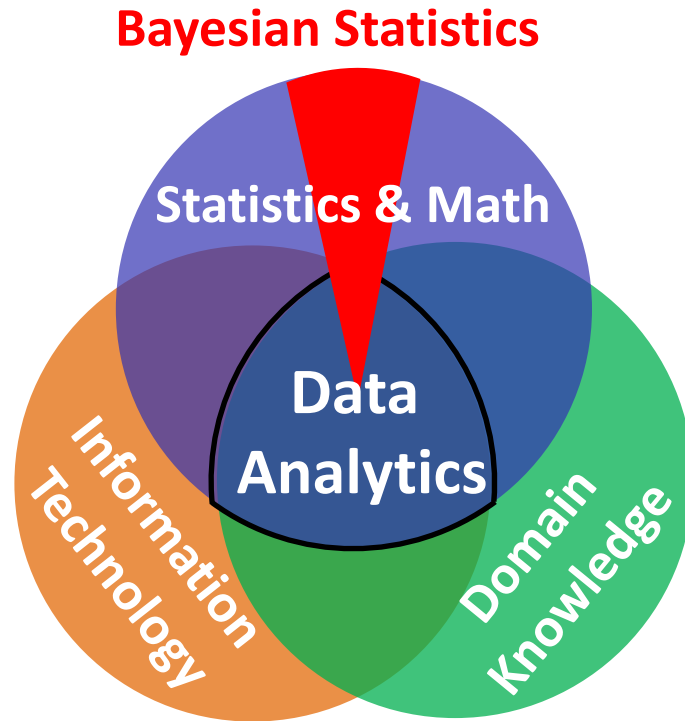
- Various Data Science and System Informatics Methods Development and Diverse Applications.



Outline

- **Background**
- **Part I - Multi-level Data Fusion**
- **Part II - Heterogeneous Data Quantification**
- **Summary**

Data Analytics



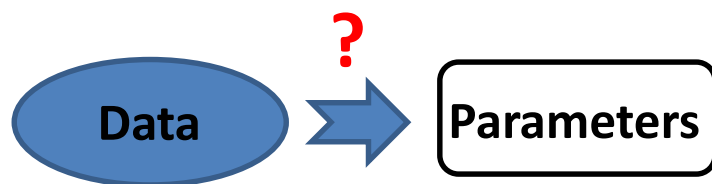
- **Focus:**

Bayesian Data Analytics for **Reliability Modeling** Improvement

Key Word: Bayesian

- Parameter Learning

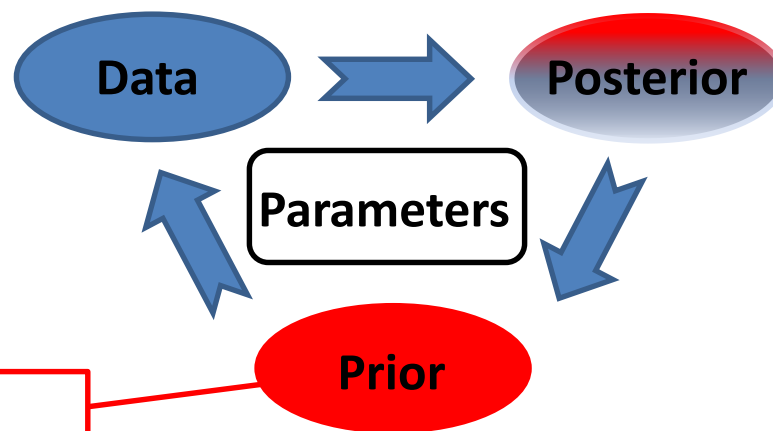
Classic Statistics



Limited Data or No Data

- External data sources
- Domain knowledge
- Non-informative prior
-

Bayesian Statistics



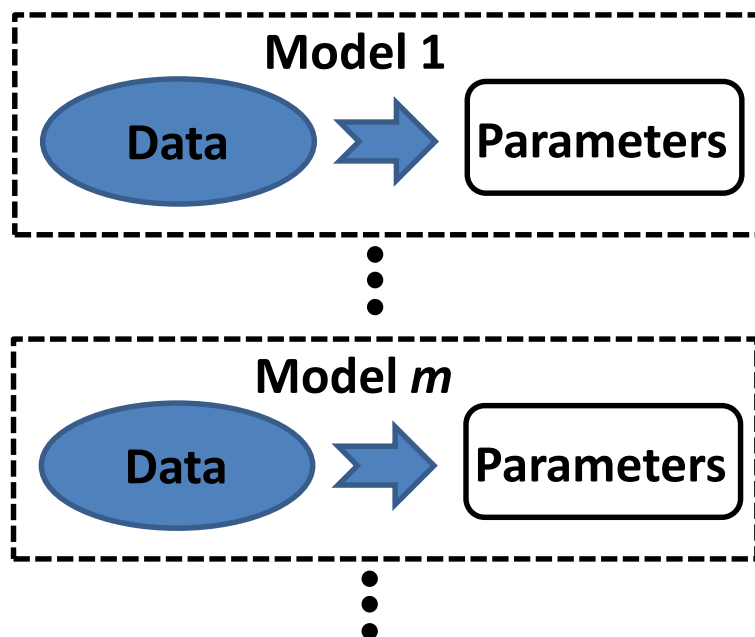
Flexible & Coherent

**Methodology I:
Multi-level Data Fusion**

Key Word: Bayesian (Cont'd)

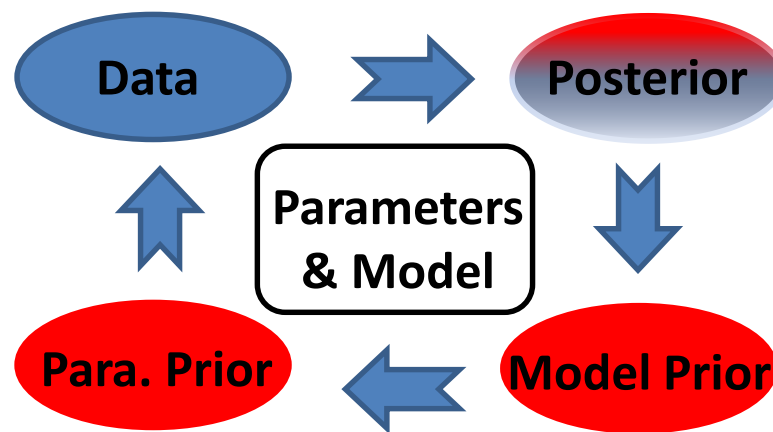
- **Model Learning**

Classic Statistics



- Underfitting/Overfitting
- Inefficient

Bayesian Statistics



Efficient & Effective

**Methodology II:
Heterogeneity Quantification**

Key Word: Reliability Modeling

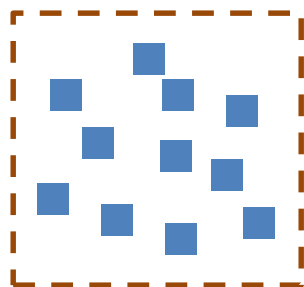
- Reliability: product quality over time^[1]

$$\Pr(\mathbf{T} > t)$$

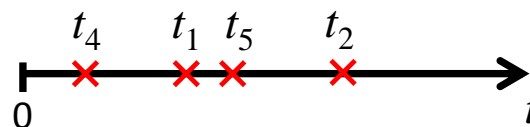
Time-to-failure

- Reliability modeling

Product Sample:



Reliability Data:



Modeling \mathbf{T}

- Data Feature

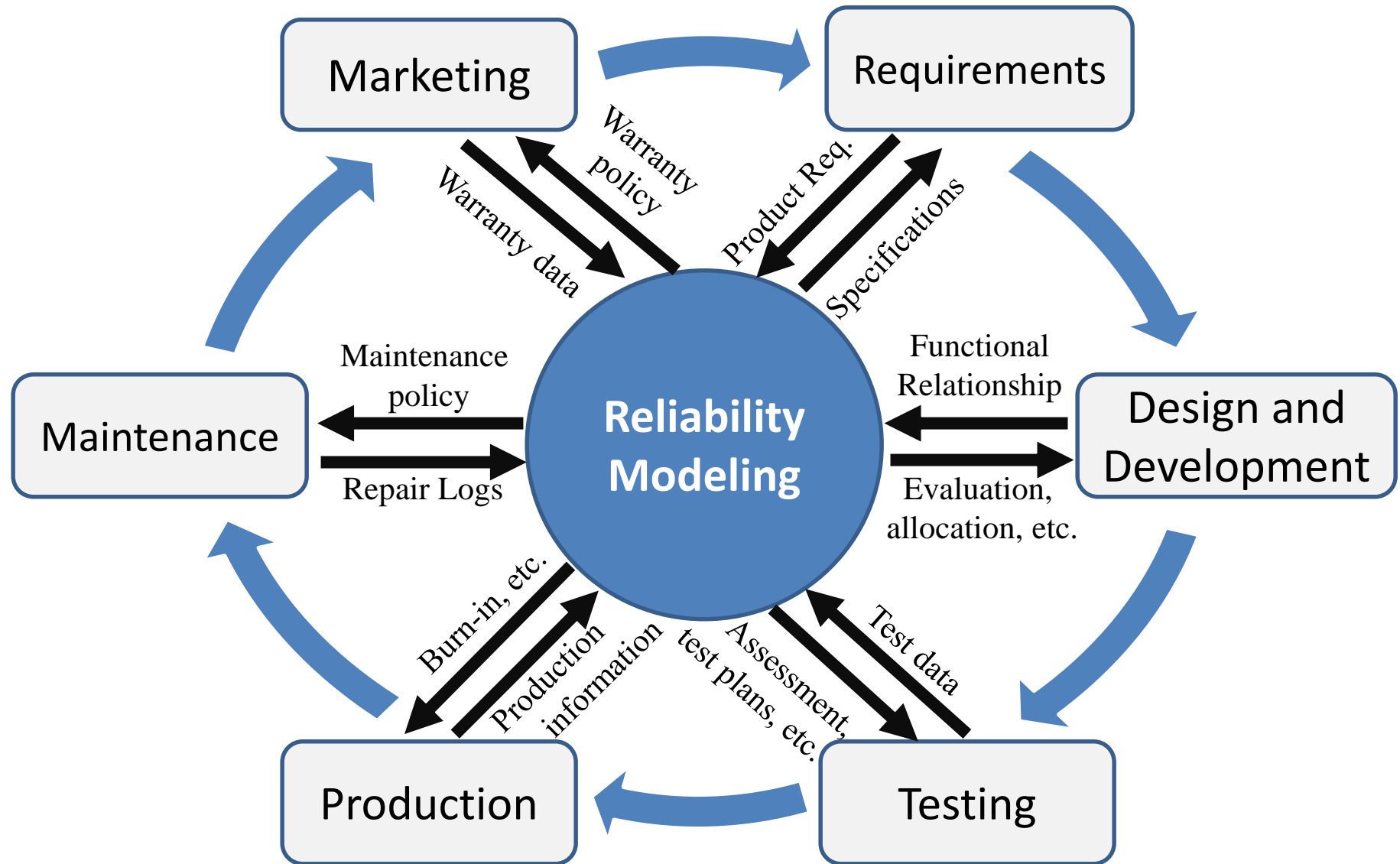
- Non-negative and asymmetric
- Covariates

- Censoring



- Others: **availability**, **heterogeneity**, etc.

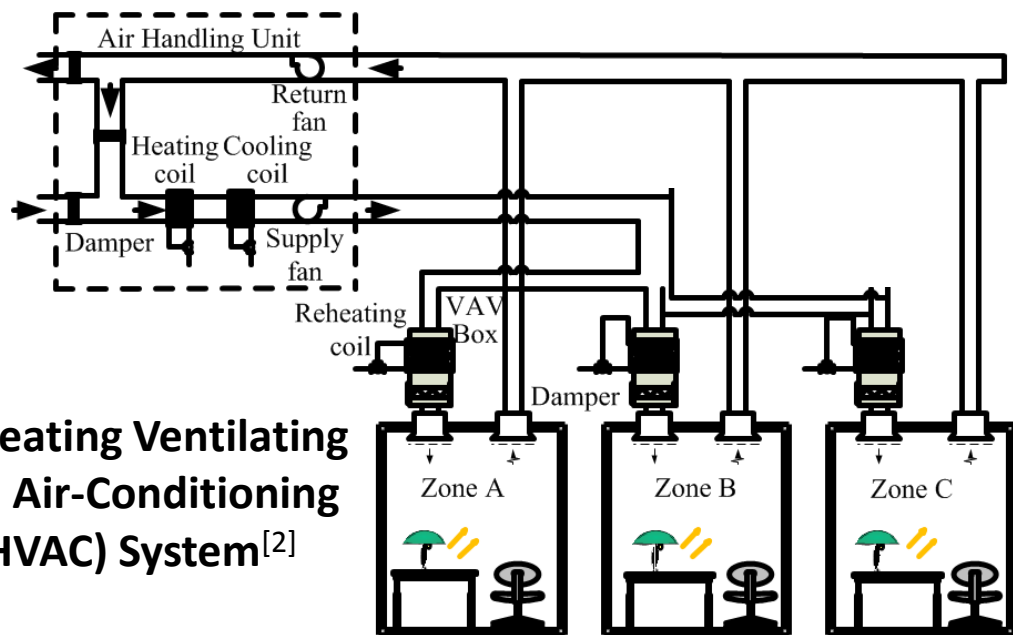
Lifecycle View of Reliability Modeling



Part I - Multi-level Data Fusion:

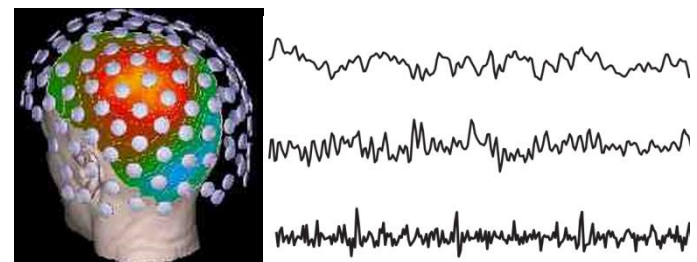
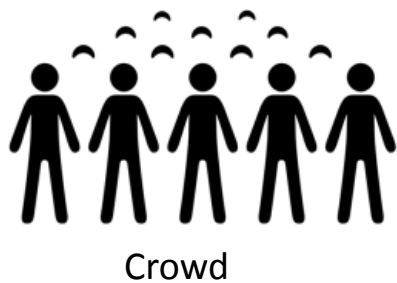
*Bayesian Multi-level Information Aggregation for Hierarchical
Systems Reliability Modeling Improvement*

Vision

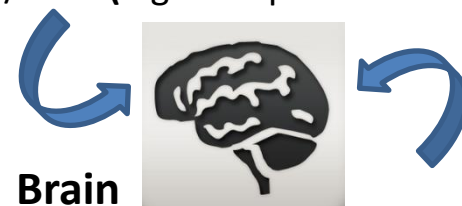


Heating Ventilating
& Air-Conditioning
(HVAC) System^[2]

Crowd Surveillance System^[4]



EEG/MEG (high-temporal-resolution)^[3]



fMRI (high-spatial-resolution)^[3]

Data-rich Environment:
Data Fusion

Focus: System Reliability

- **Performance index:** system reliability
- **Modeling Challenges:**
 - Expensive system-level tests
 - Scarce/absent engineering knowledge
 - Complex failure relationship
 - High requirement on reliability assessment



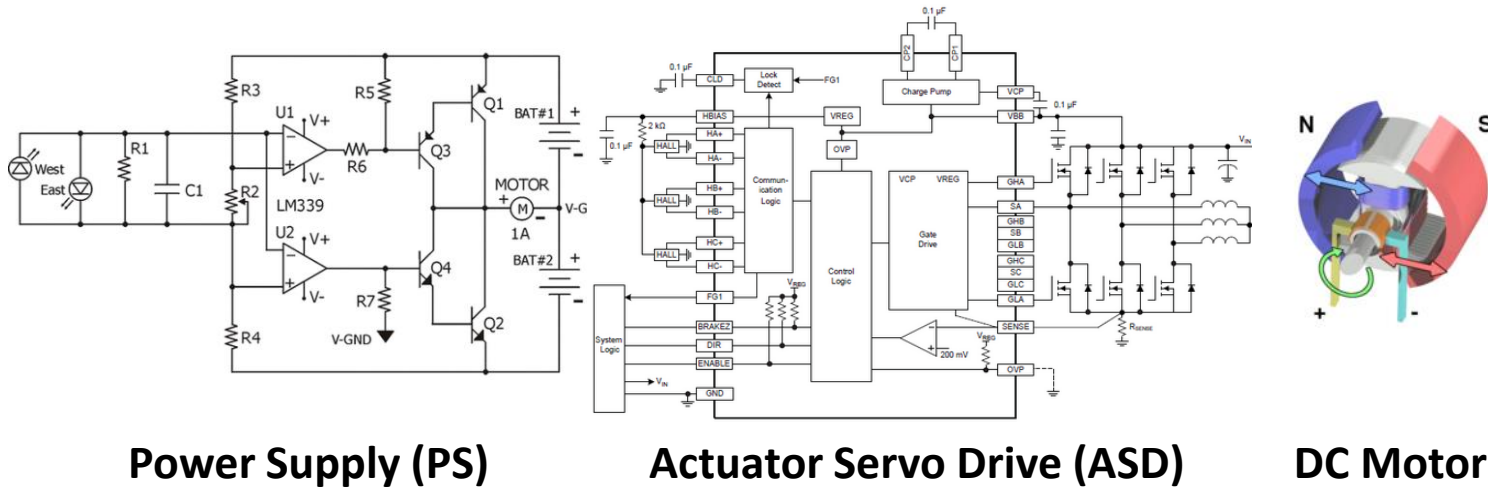
Missile
(\$10³k - \$10m)

- **Research Goal:**

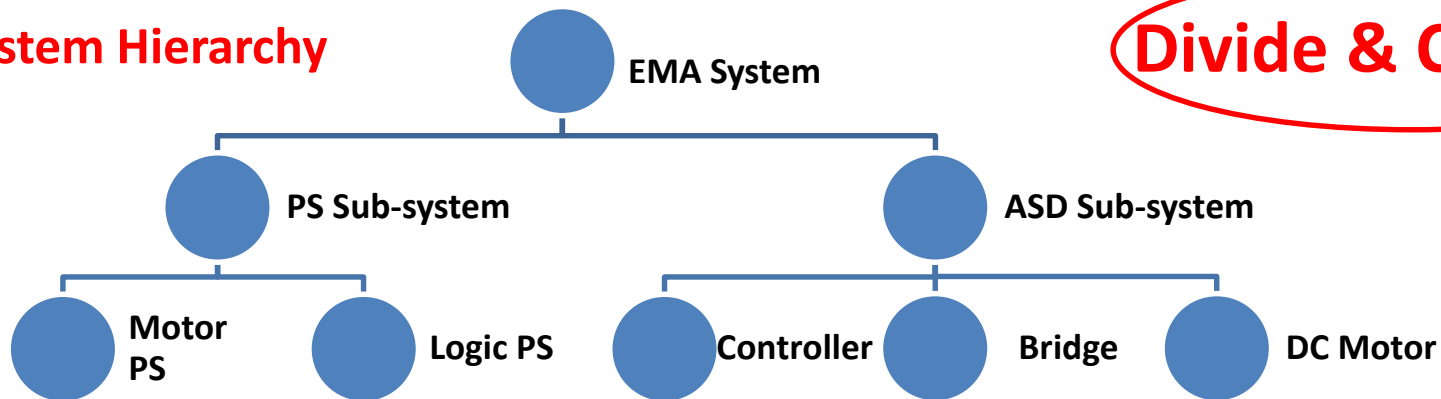
Improve system-level reliability modeling by utilizing all reliability information throughout the system in a **systematic** and **coherent** manner.

Opportunity I: Hierarchical System Structure

Electro-Mechanical-Actuator (EMA) System



Elements in
System Hierarchy



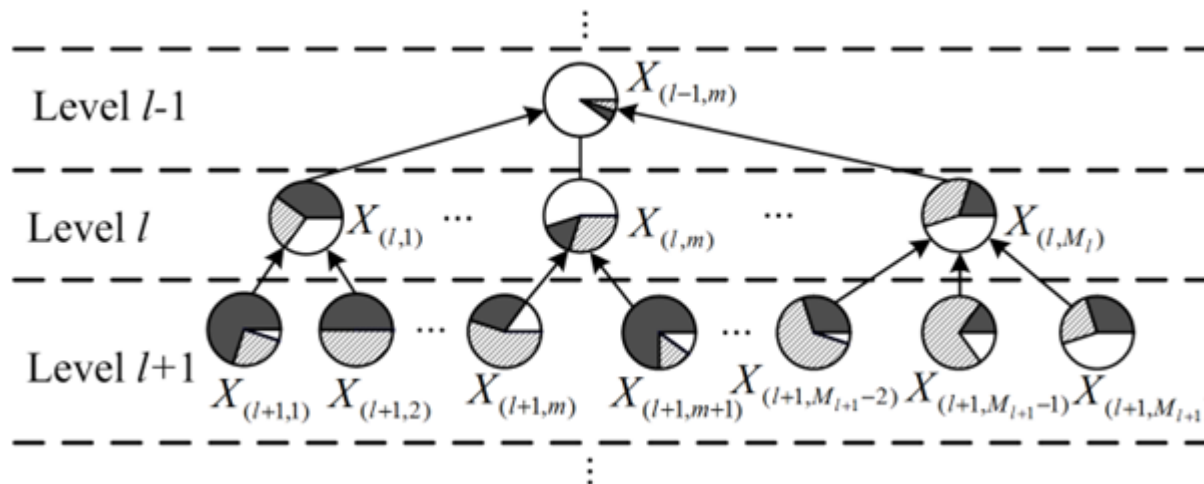
Divide & Conquer

Opportunity II: Multi-source Multi-level Data

- Multi-source reliability information:** prior knowledge (e.g., domain knowledge, historical studies, etc.) + ongoing reliability test data.

Elements	Prior knowledge	Reliability Test Data
Lower-level	Familiar	(1) Abundant (2) Limited but easy to collect
Upper-level	Unfamiliar or unknown	(1) Absent (2) Limited and/or expensive/hard to collect

- Multi-level information imbalance**



Aggregation

Reliability Information:

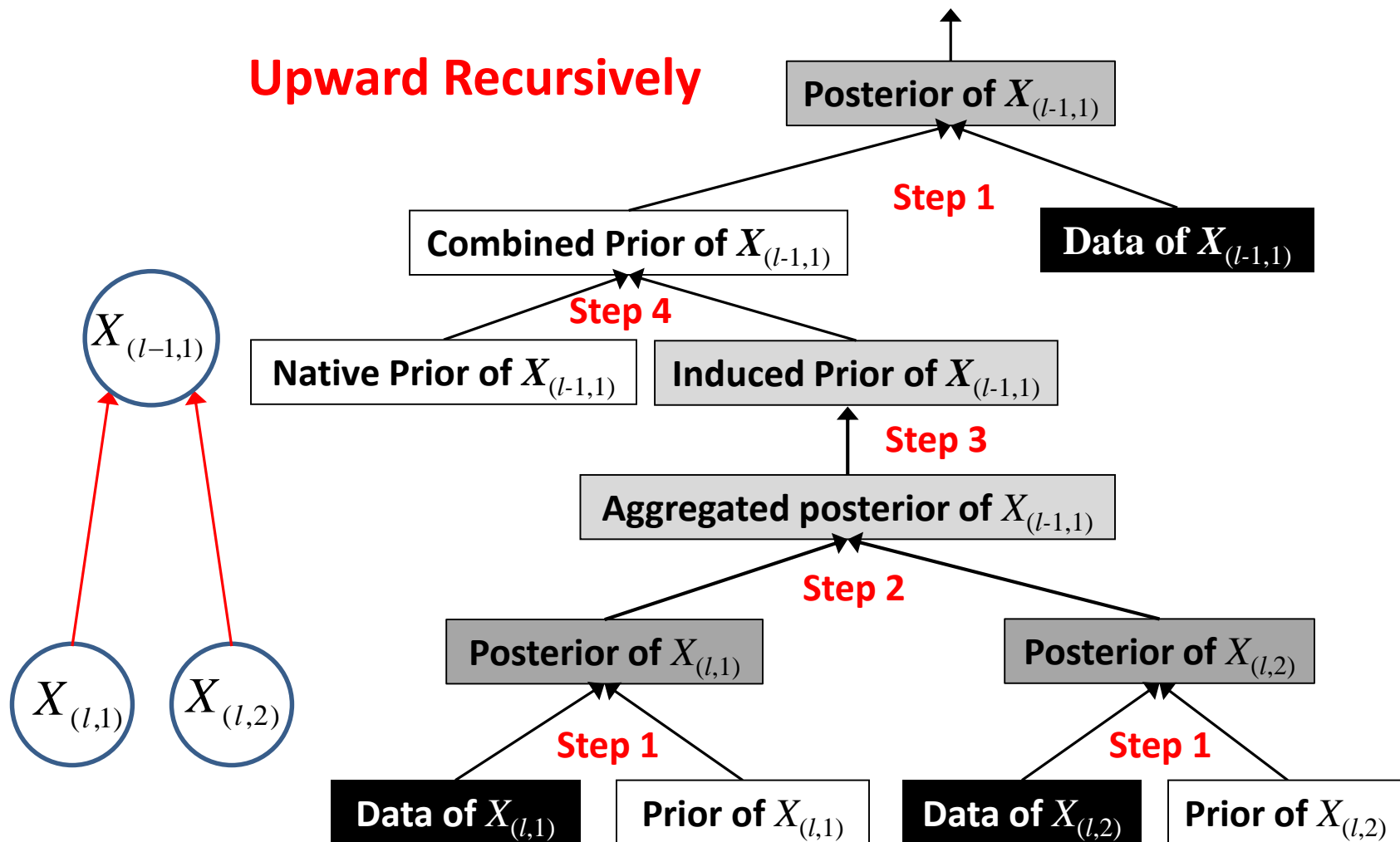
- Prior knowledge
- Reliability test data
- Absent information

State of the Art

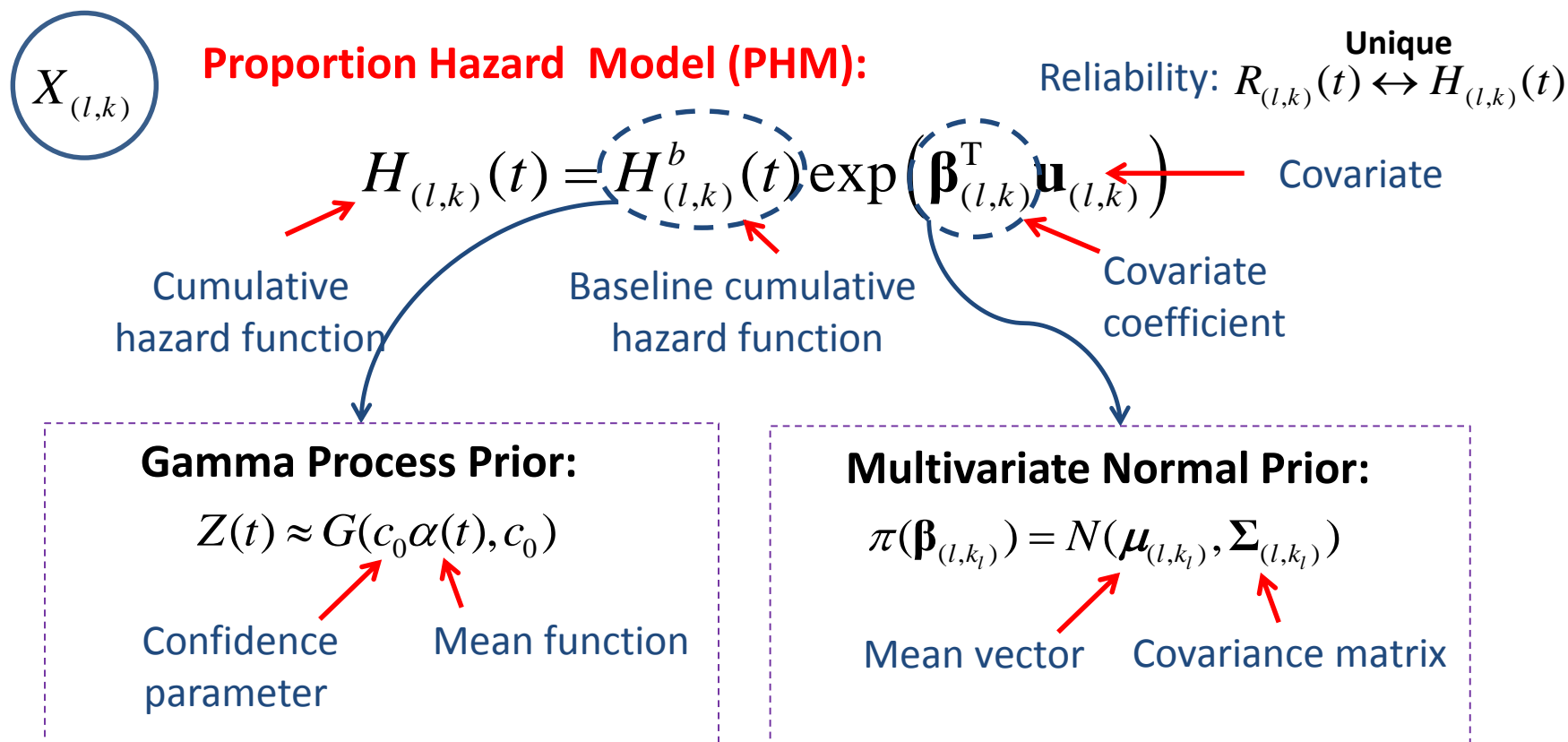
Methodology Summary		System Reliability Modeling	
		Parametric methods	Semi-parametric/non-parametric methods
Multi-level information aggregation	No	Ramamoorthy ^[5] , Camarda <i>et al.</i> ^[6] , Cui <i>et al.</i> ^[7] , Hoyland and Rausand ^[8] , Coit ^[9] , Jin and Coit ^[10] , Martz and Walker ^[11] , Hamada <i>et al.</i> ^[12] , etc.	Klein and Moeschberger ^[13] , Meeker and Escobar (Chapter 3) ^[14] , Ibrahim <i>et al.</i> ^[15]
	Yes	Martz <i>et al.</i> ^[16] , Martz and Walker ^[17] , Hulting and Robinson ^[18]	To be presented

- **Features of the proposed model:**
 - Failure-time data with covariates and censoring
 - Semi-parametric modeling
 - Information aggregation from lower levels

Overview of the Proposed Work



Modeling of Individual Element



Baseline cumulative hazard increments:

$$\Delta H_{j,(l,k)}^b \sim \text{Gamma}(c_0(\alpha(s_j) - \alpha(s_{j-1})), c_0)$$

Carry information for aggregation

Aggregation Procedure: Step 1

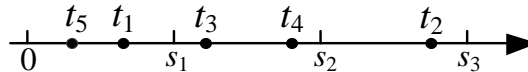
- Step 1** – Compute the posterior (lower-level element):

Joint Posterior \propto **Likelihoods** \times **Joint Priors**:

$$p(\boldsymbol{\beta}_{(l,k)}, \Delta H_{j(l,k)}^b \mid \Omega_{(l,k)}) \propto \underbrace{\mathcal{L}(\boldsymbol{\beta}_{(l,k)}, \Delta H_{j(l,k)}^b \mid \Omega_{(l,k)})}_{\text{Failure-time data with covariates and censoring}} \underbrace{\pi(\boldsymbol{\beta}_{(l,k)})\pi(\Delta H_{j(l,k)}^b)}_{\text{Prior knowledge}}$$

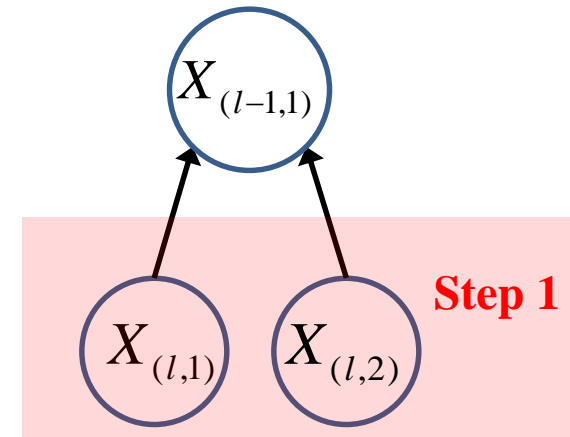
Integration of data and prior

Example:



t_n : the actual failure time stamp of test unit n

Bayesian PHM integrates the reliability prior knowledge and failure data



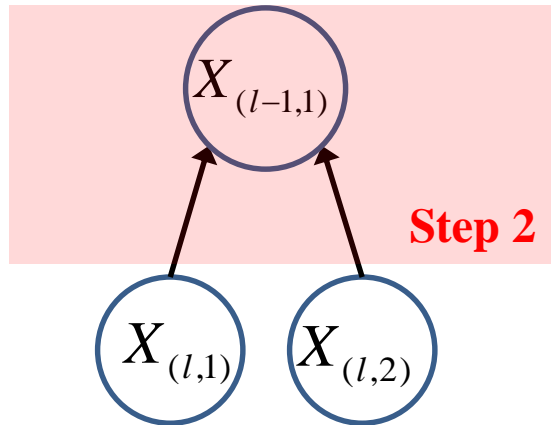
Aggregation Procedure: Failure Relationship

- Failure relationship between two levels:

General Relationships

Reliability functions: $R_{(l-1,k)}(t) = f(R_{(l,\kappa)}(t)), \kappa \in \mathbf{Q}_{(l-1,k)}$

Baseline cumulative hazard increments: ${}^A\Delta H_{j,(l-1,k)}^b = g(\Delta H_{j,(l,\kappa)}^b), \kappa \in \mathbf{Q}_{(l-1,k)}$



Example: Series configuration

Aggregated $\rightarrow {}^A R_{(l-1,1)}(t) = R_{(l,1)}(t) R_{(l,2)}(t)$

$\rightarrow {}^A \Delta H_{j(l-1,1)}^b(t) = \Delta H_{j(l,1)}^b(t) + \Delta H_{j(l,2)}^b(t)$

Information is aggregated through ΔH_j^b based on failure relationships

Aggregation Procedure: Steps 2-3

- **Step 2** - Aggregate the posterior:

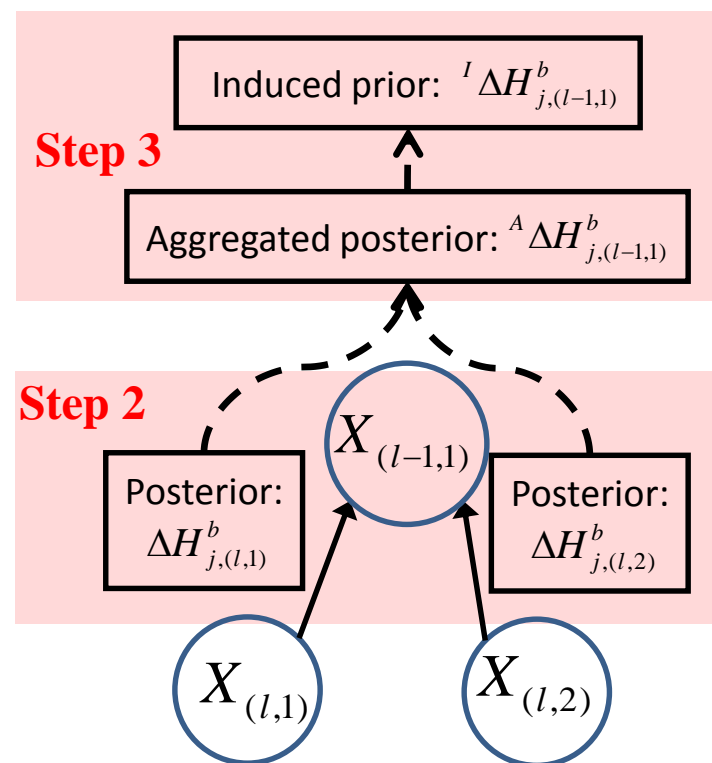
Aggregated posterior: ${}^A\Delta H_{j,(l-1,1)}^b = g(\Delta H_{j,(l,\kappa)}^b), \kappa = 1, 2$

- **Step 3** - Approximate the induced prior:

Induced prior: ${}^I\Delta H_{j,(l-1,1)}^b \leftarrow {}^A\Delta H_{j,(l-1,1)}^b$

${}^I\Delta H_{j,(l-1,1)}^b \sim \text{Gamma}({}^I\eta_{j,(l-1,1)}, {}^I\lambda_{j,(l-1,1)})$

(Validate by K-S goodness fitness test)



Aggregation Procedure: Step 4

- **Step 4** – Combine the native prior and the induced prior:

Combined prior: ${}^C\Delta H_{j,(l-1,1)}^b \sim \text{Gamma}({}^C\eta_{j,(l-1,1)}, {}^C\lambda_{j,(l-1,1)})$

$${}^C\eta_{j,(l-1,1)} = w^I\eta_{j,(l-1,1)} + (1-w)^N\eta_{j,(l-1,1)}$$

Weighting factor: $0 \leq w \leq 1$

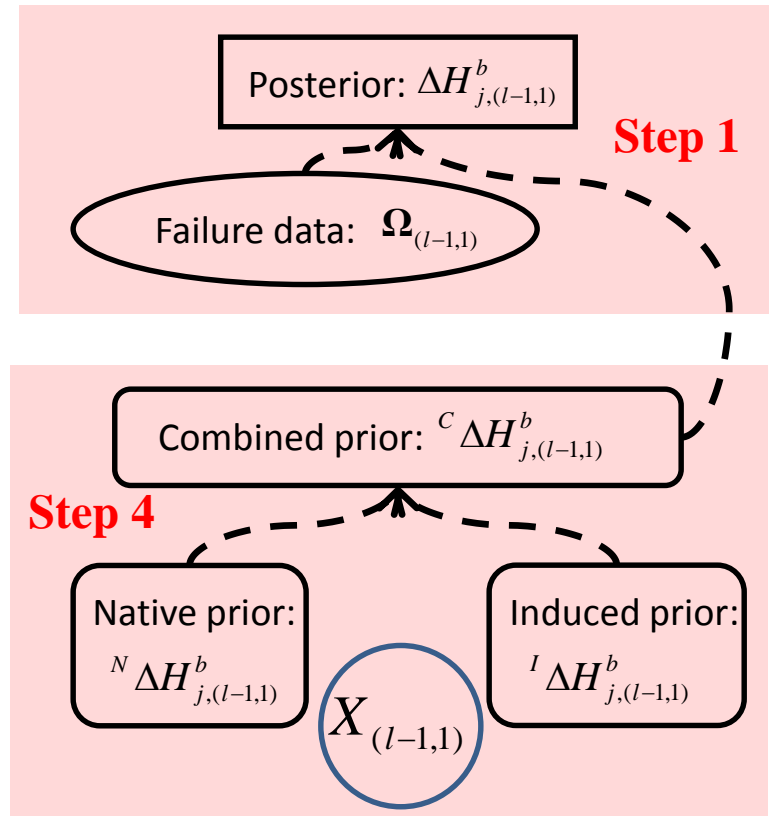
$${}^C\lambda_{j,(l-1,1)} = w^I\lambda_{j,(l-1,1)} + (1-w)^N\lambda_{j,(l-1,1)}$$

w : balance native prior and induced prior

- **Step 1** – Compute the posterior (higher-level element):

Similar Bayesian inference

$${}^C\Delta H_{j,(l-1,1)}^b \sim \text{Gamma}({}^C\eta_{j,(l-1,1)}, {}^C\lambda_{j,(l-1,1)})$$

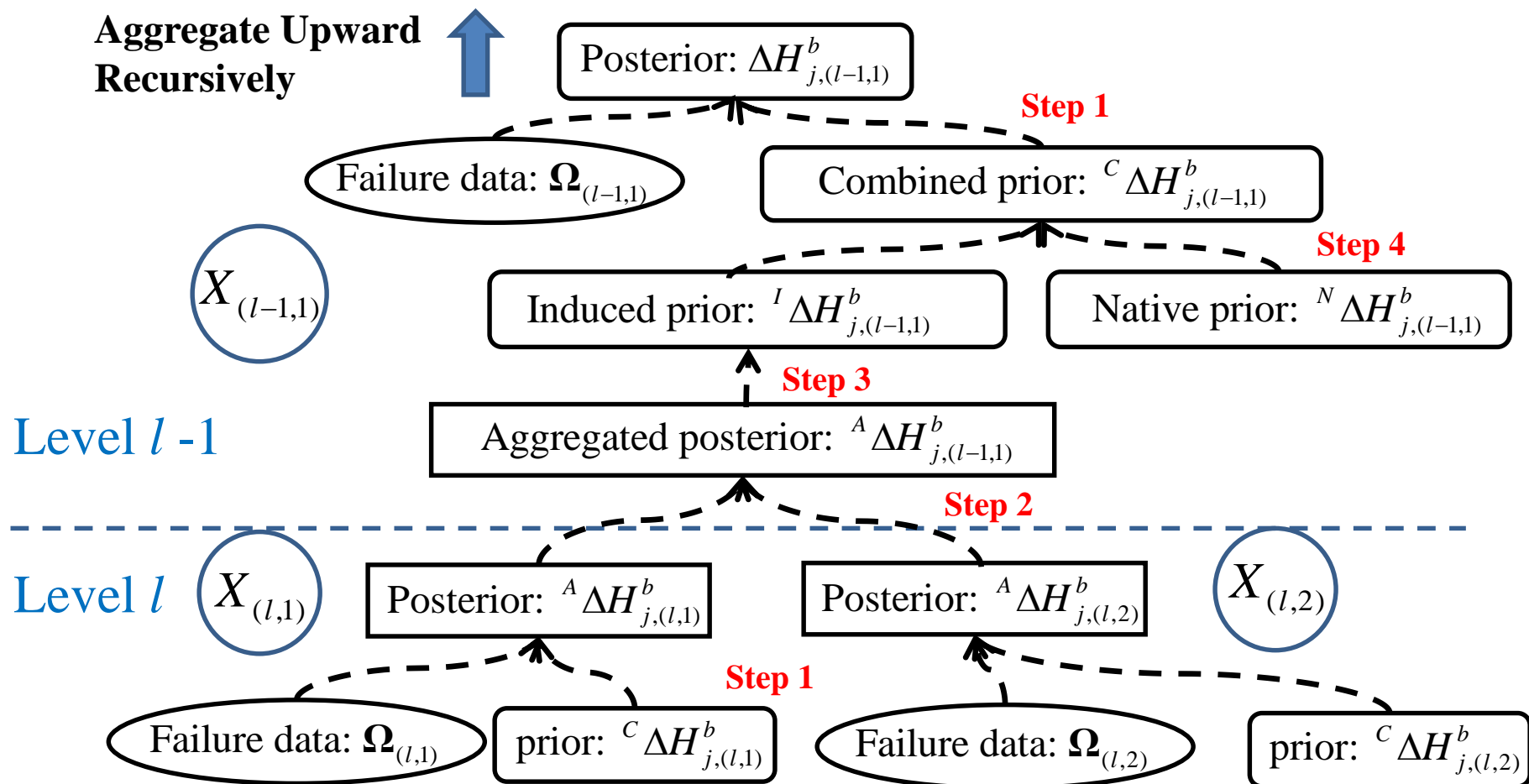


Information Aggregation: Procedure Review

• **Recursive**

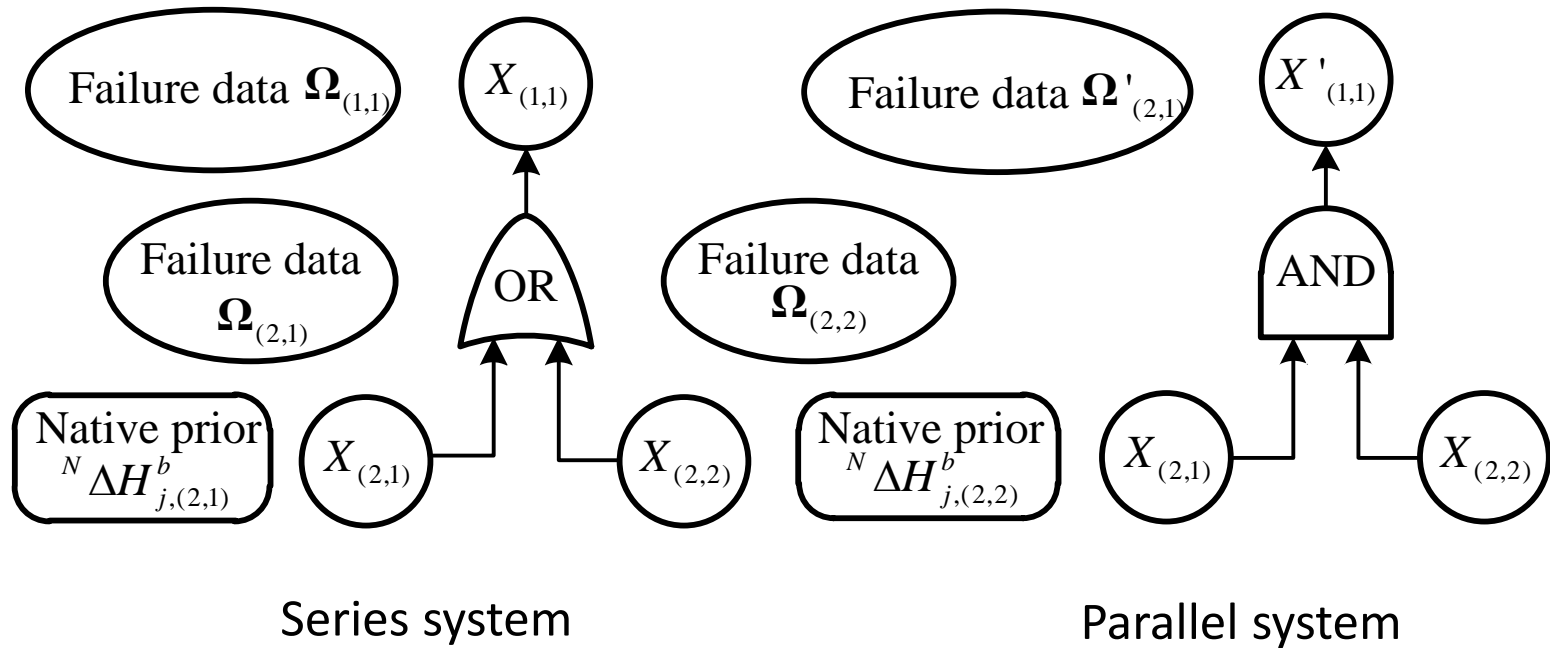
• **Flexible**

• **Generic**



Numerical Case Study

- A two-level hierarchical system with 3 elements
- One covariate u is considered with binary values: 0/1
- Test data are simulated with 30 intervals



Information Aggregation

- Steps 1-2: Compute and aggregate the posteriors of components:

$$^A \Delta H_{j,(l-1,k)}^b = g(\Delta H_{j,(l,\kappa)}^b), \kappa \in \mathbf{Q}_{(l-1,k)}$$

- Step 3: Approximate the aggregated posteriors into the induced priors:

	Series structure			Parallel structure		
Variable (1,1)	Shape parameter	Rate parameter	<i>p</i> -value of K-S test	Shape parameter	Rate parameter	<i>p</i> -value of K-S test
$^I \Delta H_{(1,1)(2,1)}^b$	27.4611	107.8274	0.4829	7.7291	547.8775	0.6664
$^I \Delta H_{(1,1)(2,1)}^b$	26.7808	93.0126	0.5727	13.3783	309.2855	0.5727
$^I \Delta H_{3,(2,1)}^b$	29.0416	69.9600	0.4489	17.9232	187.4683	0.5727
(1,1)
$^I \Delta H_{(1,1)(2,1)}^b$	2.8181	10.1614	0.4489	2.6652	19.7447	0.6852
$^I \Delta H_{30,(2,1)}^b$	2.7292	9.7480	0.9011	2.6277	19.2961	0.7410

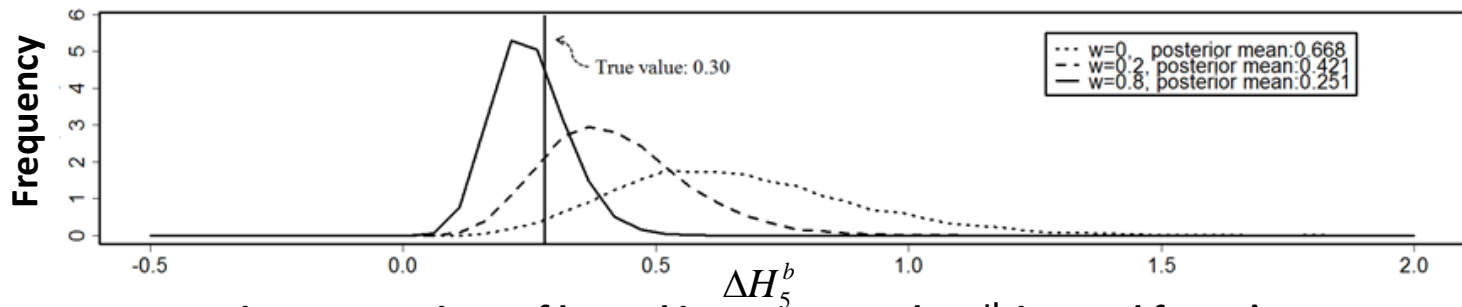
Information Aggregation (Cont'd)

- Step 4: Combine the induced priors and the native priors

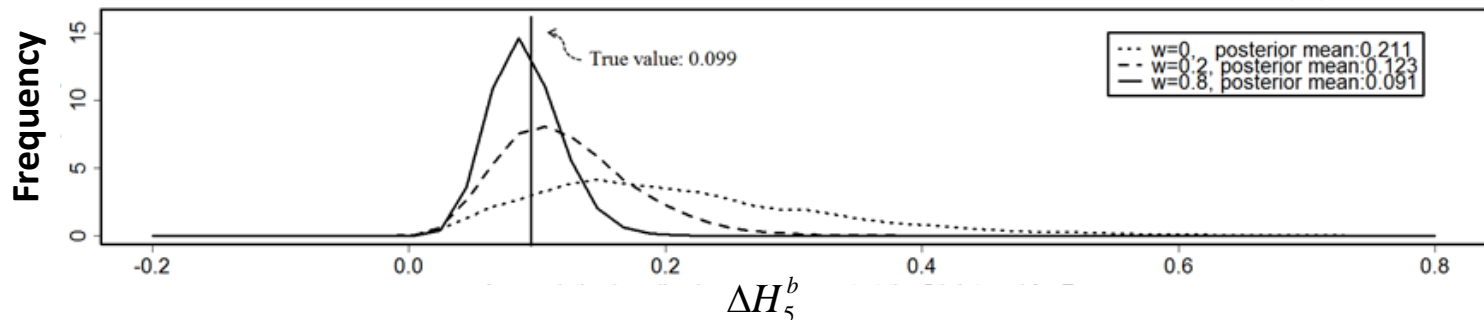
$w=0, 0.2, 0.8$ Different effects of information aggregation

- Step 1: Compute posteriors for the system

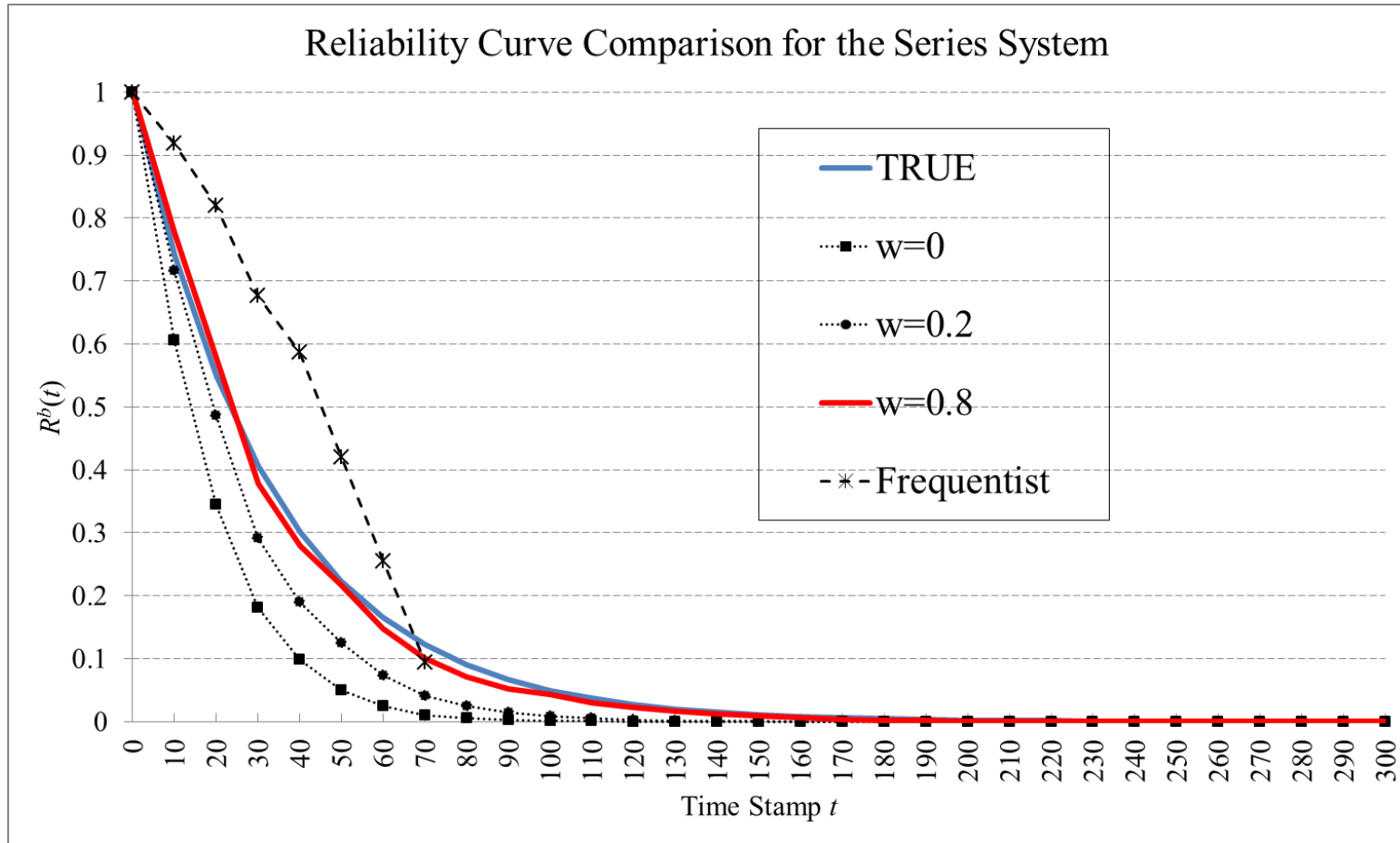
Posteriors comparison of hazard increment at the 5th interval for $X_{(1,1)}$



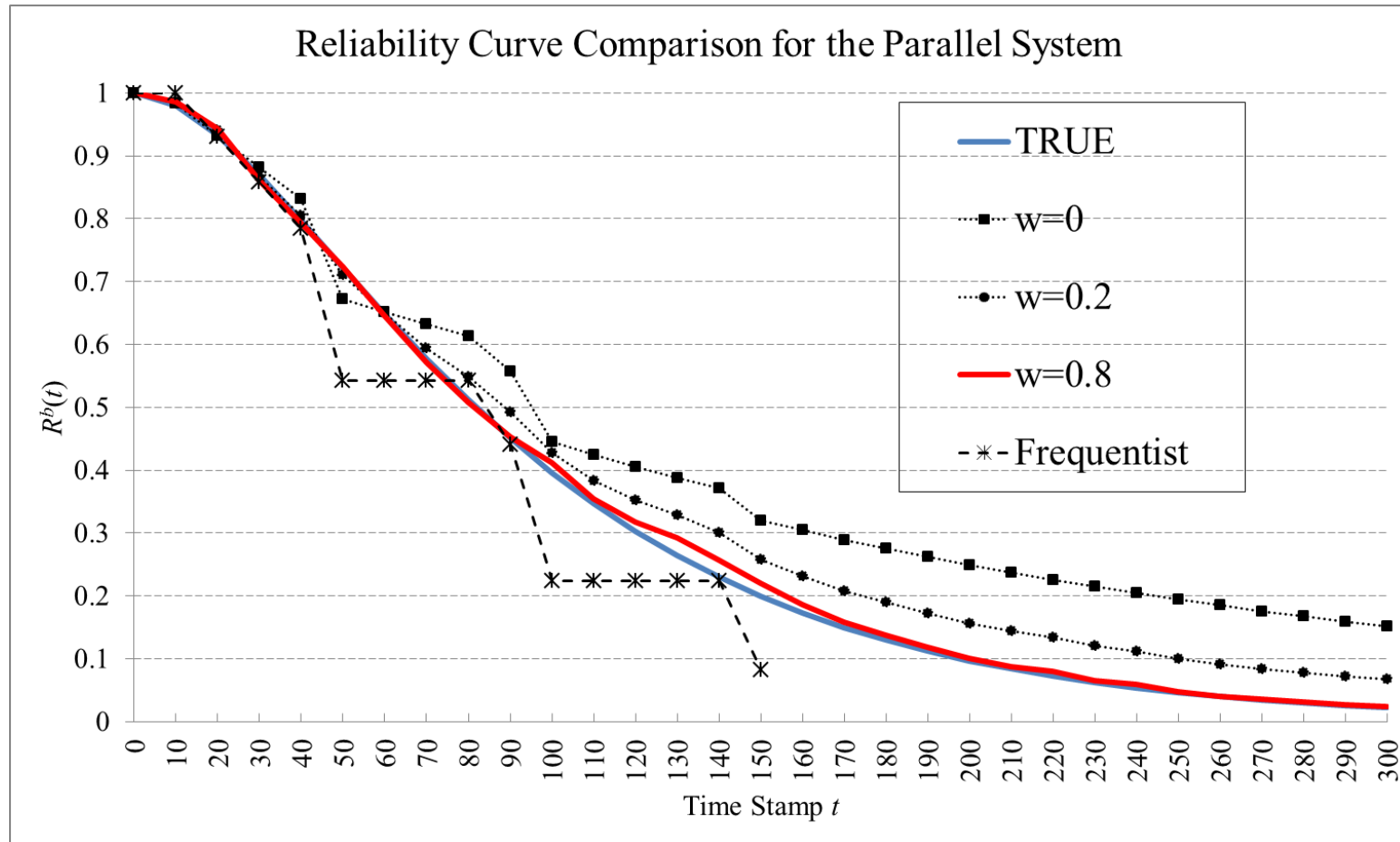
Posteriors comparison of hazard increment at the 5th interval for $X'_{(1,1)}$



Series System Reliability Curve Comparisons



Parallel System Reliability Curve Comparisons

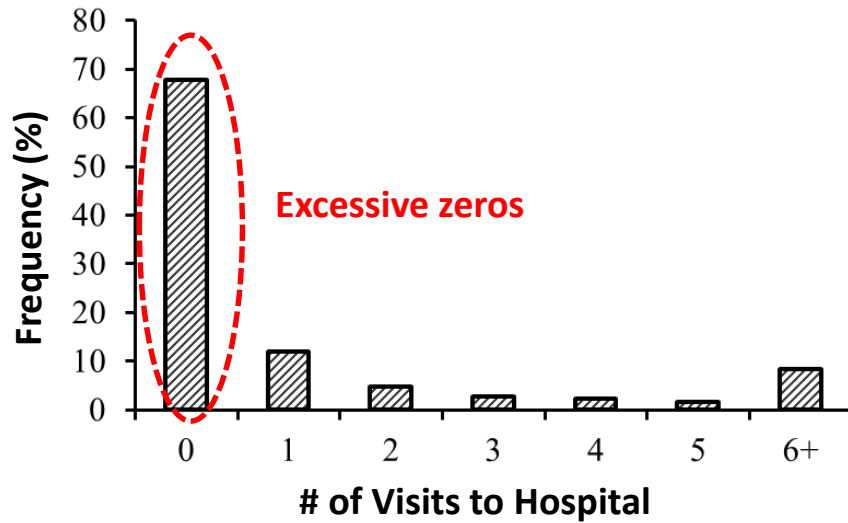


Part II - Heterogeneous Data Quantification:

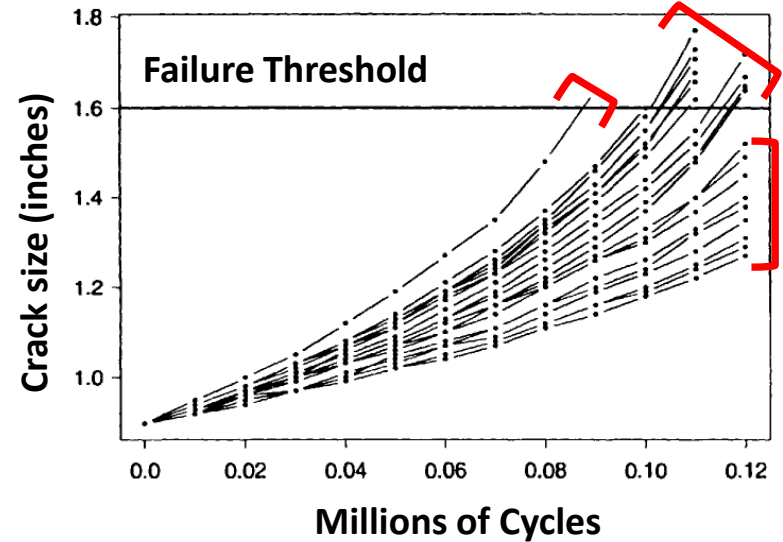
Bayesian Modeling and Learning of Heterogeneous Time-to-Event Data with an Unknown Number of Sub-populations

Vision

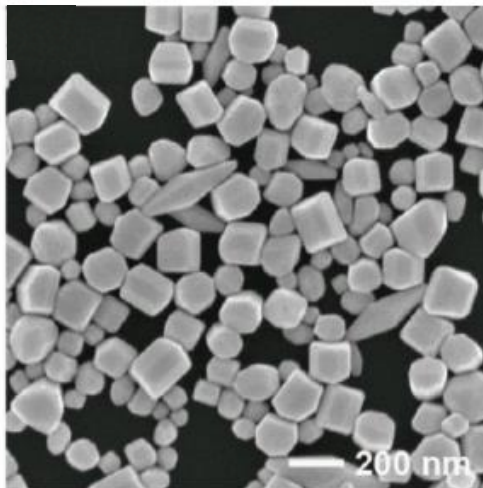
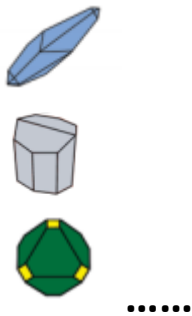
Health Care Utilization Data^[19]



Alloy Fatigue Crack Size Data^[20]



Nanocrystals
Growth Data^[21]



Heterogeneous Populations:
Heterogeneous Data
Quantification

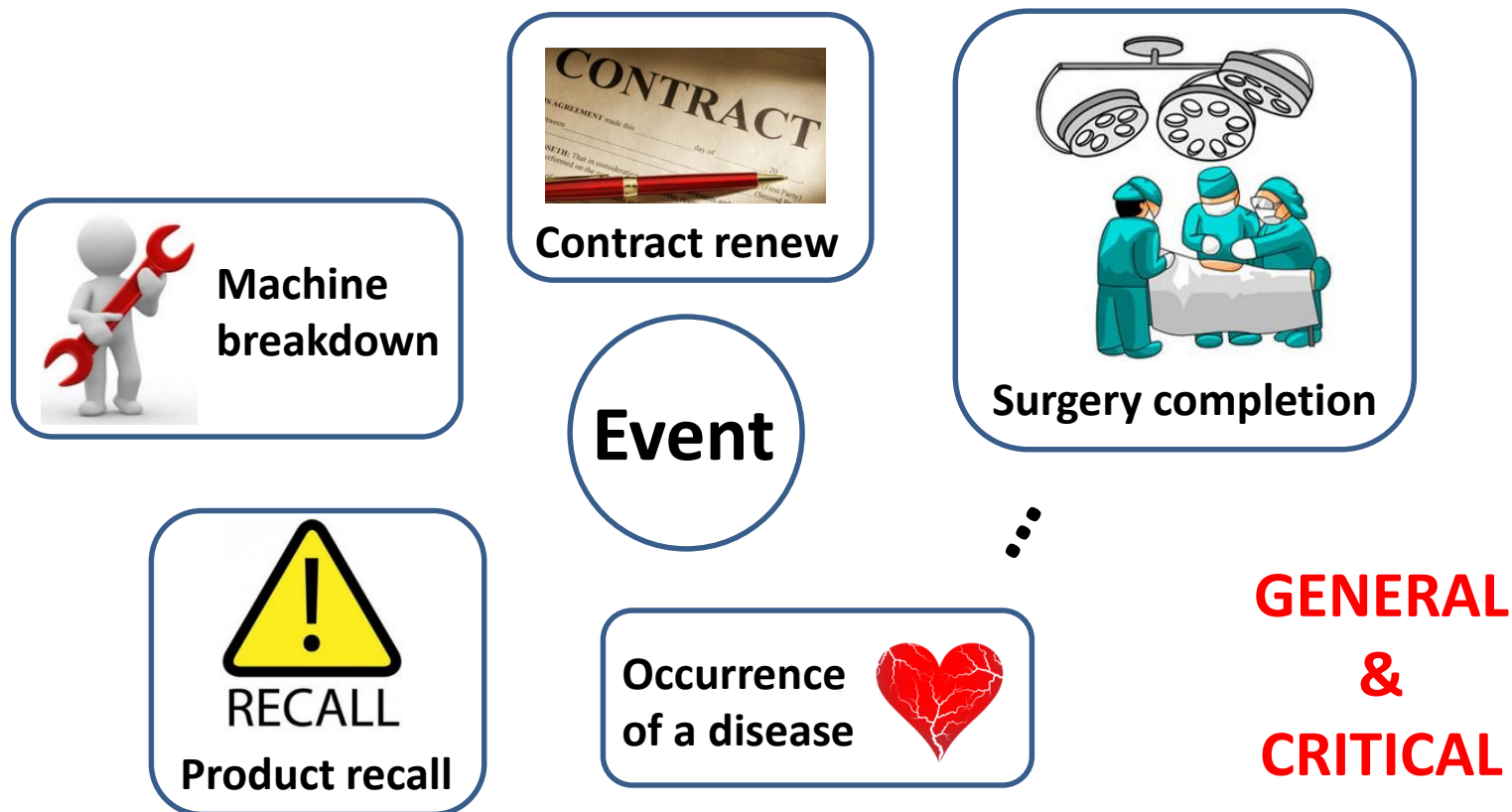
How many?

How to model?

Focus: Time-to-Event Data

- Time-to-event (TTE) data is important

TTE: Time to occurrence of an **event** of interest

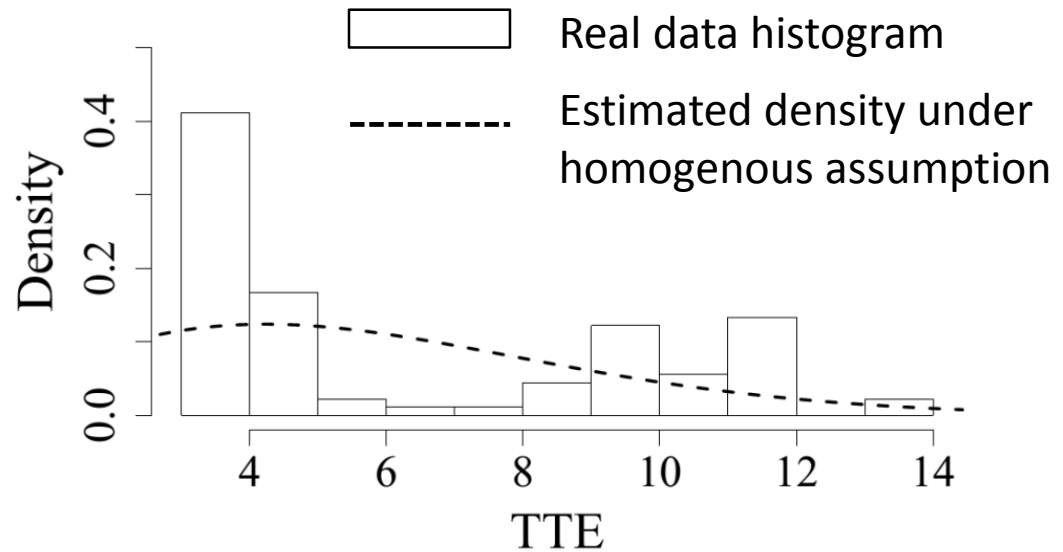


TTE Heterogeneity

- TTE: assembly time



Intelligent Robotic
Assembly System^[22]



Histogram of data at the **SAME** process setting

- ~~Homogenous assumption~~
- **Reason:** heterogeneous products quality, etc.

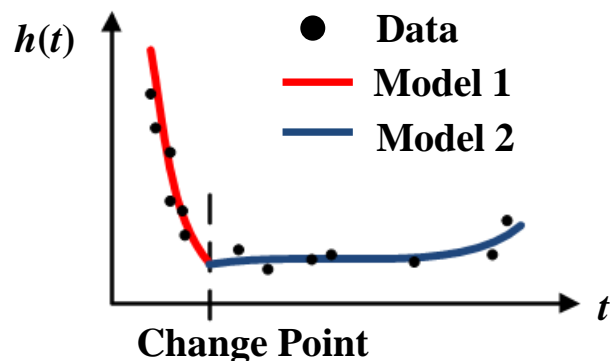
TTE Heterogeneity (Cont'd)

- Reliability examples
- **Semiconductor industry**^[23]: infant mortality failures
Reason: manufacturing defects, assembly errors, etc.
- **Automobile industry**^[24]: early failures
Reason: material quality, unverified design changes, etc.
- **Industry with evolving technology**^[25]: heterogeneity especially critical
Reason: immature technology

Q: How to model TTE heterogeneity?

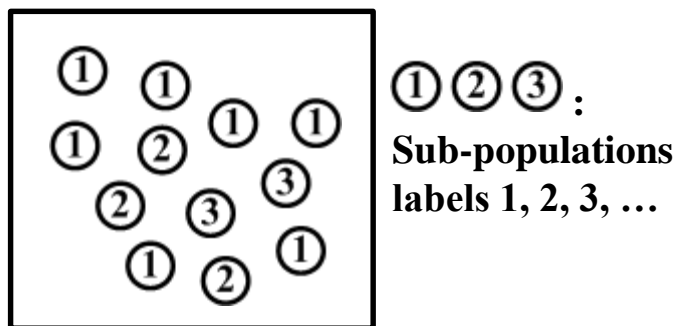
Heterogeneity Modeling of TTE

- **Change point model**^[26-28]:
- **Mixture model**^[31,32]:

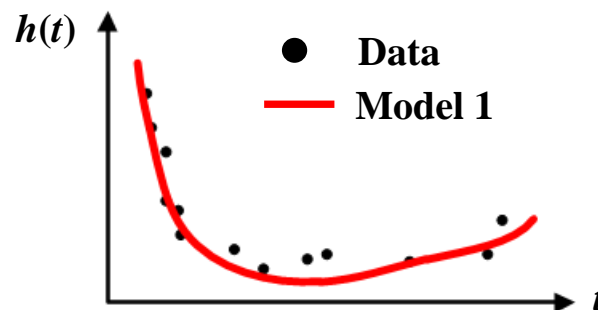


Limitation: different domains

- **Frailty model**^[29,30]:

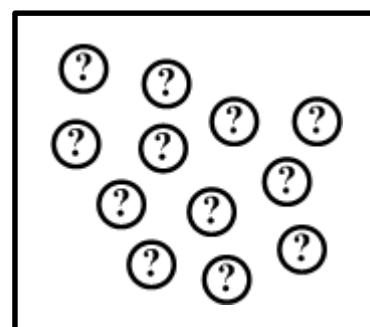


Limitation: known membership



Scope

(1) One model under entire domain



(2) Unknown membership

(3) Meaningful interpretation;
(4) Feedback information.

Mixture Model: Gaps and Solutions

Existing Method	Limitation	Advantage	Solution
Known the number of sub-populations (m) ^[33,34]	subjective	Unknown m , learned from data	objective
Model estimation + model selection (e.g., LRT, AIC) ^[35,36]	Two-step	Bayesian formulation	Joint model estimation and selection
Mixtures of distributions ^[32,37,38,41]	w/o covariates	Mixtures of regressions	w/ covariates
Conjugate prior ^[39,40]	Restrictive	Non-conjugate prior	Generic

Expected Features of the Proposed Work

- Assuming an **unknown** # of sub-populations
- Considering influence of possible **covariates**
- Achieving **joint** model estimation and model selection
- Comprehensive treatment of **non-conjugate** priors

Mixture Model: Known m

- j^{th} homogenous sub-population:

$$h_j(t | \mathbf{x}) = h_j^b(t) \exp(\boldsymbol{\beta}_j^T \mathbf{x})$$

Hazard function \rightarrow TTE \rightarrow Baseline Hazard function \rightarrow Covariate coefficients \rightarrow Covariates

Benefits: (1) Covariates; (2) Flexible; (3) $h_j(t) \leftrightarrow f_j(t)$ **Unique**

- The overall heterogeneous population:

$$g(t | \Theta^m, \mathbf{x}) = \sum_{j=1}^m w_j f_j(t | \theta_j, \mathbf{x})$$

Population pdf \rightarrow All unknowns \rightarrow Sub-population proportion \rightarrow Sub-population pdf \rightarrow Sub-population unknowns

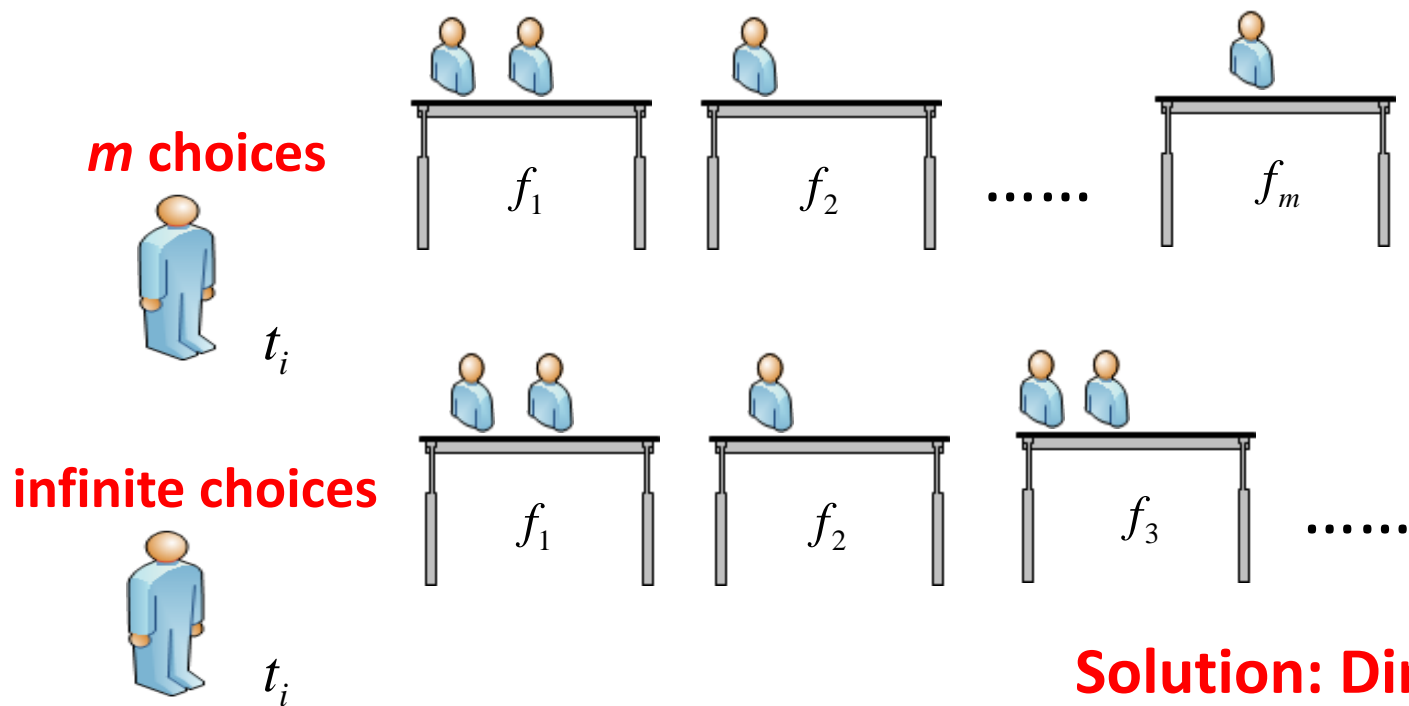
m known

What if unknown

Mixture Model: Unknown m

- Finite mixture model:

$$g(t \mid \Theta^m, \mathbf{x}) = \sum_{j=1}^{\overset{m \text{ known}}{\textcircled{m}}} w_j f_j(t \mid \theta_j, \mathbf{x})$$



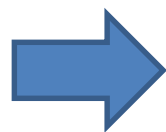
Solution: Dirichlet Process

Mixture Model: Unknown m (Cont'd)

- Bayesian hierarchical formulation:

$$t \mid \mathbf{x}, \boldsymbol{\theta} \sim f(\cdot \mid \mathbf{x}, \boldsymbol{\theta}),$$

$$\boldsymbol{\theta} \mid P \sim P$$



$$g(t \mid \boldsymbol{\Theta}, \mathbf{x}) = \sum_{j=1}^{\infty} w_j f_j(t \mid \boldsymbol{\theta}_j, \mathbf{x})$$

$$P \mid \alpha, P_0 \sim \mathbf{DP}(\alpha P_0(\cdot))$$

A random
distribution

Dirichlet process

Positive scalar

Base distribution

finite mixture:

$$\sum_{j=1}^m$$



infinite mixture:

$$\sum_{j=1}^{\infty}$$

New formulation:

- (1) **no restriction** on m
- (2) m learned **objectively**
- (3) **Joint** model estimation and model selection

Estimation Challenges

Data: $\mathbf{D} = \{t_i, \Delta_i, \mathbf{x}_i\}_{i=1}^n$

Right-censored indicator

Unknowns: $\Theta = \{w_j, \boldsymbol{\beta}_j, k_j, \eta_j\}_{j=1}^{\infty}$

Weibull baseline

shape

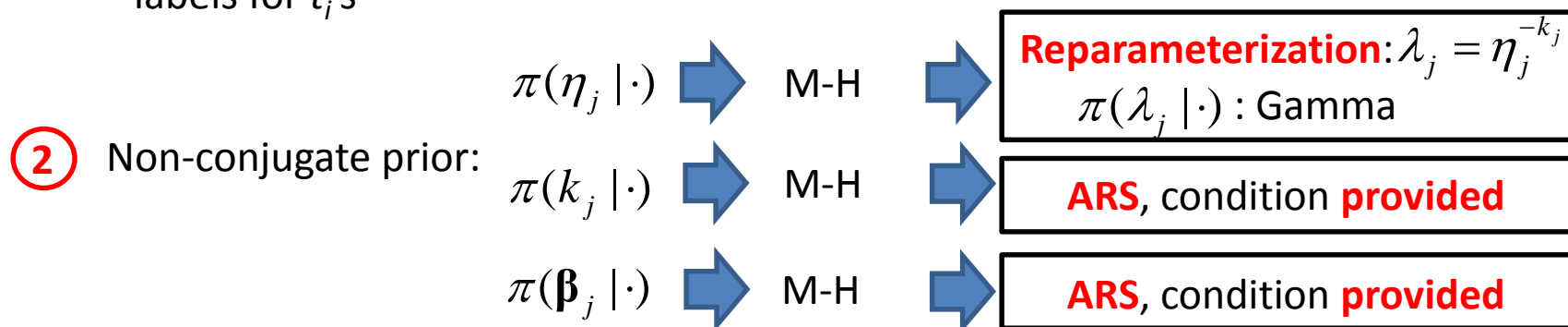
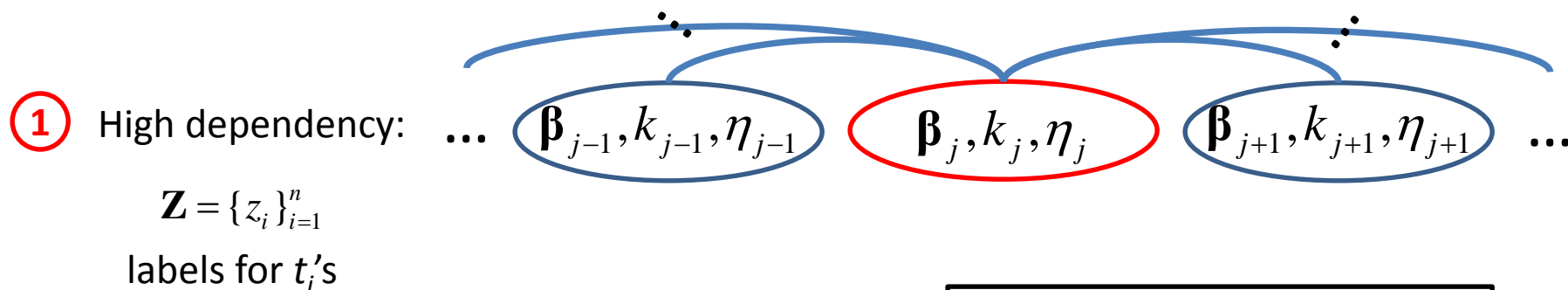
scale

Joint posterior:

$$\pi(\Theta | \mathbf{D}) \propto \prod_{i=1}^n \left(\sum_{j=1}^{\infty} w_j f_j(t_i | \boldsymbol{\beta}_j, k_j, \eta_j, \mathbf{x}_i) \right)^{\Delta_i} \cdot \left(\sum_{j=1}^{\infty} w_j R_j(t_i | \boldsymbol{\beta}_j, k_j, \eta_j, \mathbf{x}_i) \right)^{1-\Delta_i} \cdot \pi(\Theta)$$

- Challenges:
- ① **High** dependency \Rightarrow Slow/failed convergence
 - ② **Non-conjugate** prior \Rightarrow Sampling difficulty
 - ③ **Infinite** # of unknowns \Rightarrow Computationally formidable

Estimation Solutions



Metropolis-Hasting (M-H)^[41]:

- Pros: General purpose
- Cons: Tuning problem, samples auto-correlated

Adaptive Rejection Sampling (ARS)^[42]:

- Condition-based
- No tuning, samples independent

③ Infinite # of unknowns: slice-sampling techniques^[40]: $j=1,2,\dots,J^*$, where J^* is **finite**

Realized Features of the Proposed Work

- **Unknown** # of sub-populations: **Dirichlet process**
- **Covariates**: **hazard regression**
- **Joint** model estimation & selection: **Bayesian model**
- **Non-conjugate** priors: **a series of sampling techniques**

Numerical Case Study: Effectiveness

- **Simulation setup**
- 2-mixture of Weibull regression
- Single covariate $X \sim \text{Unif}(0,5)$
- Right-censored time $1.0\text{e}+5$

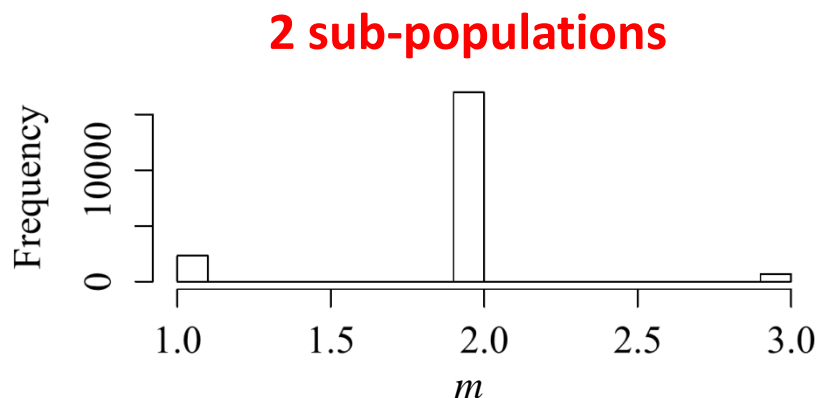
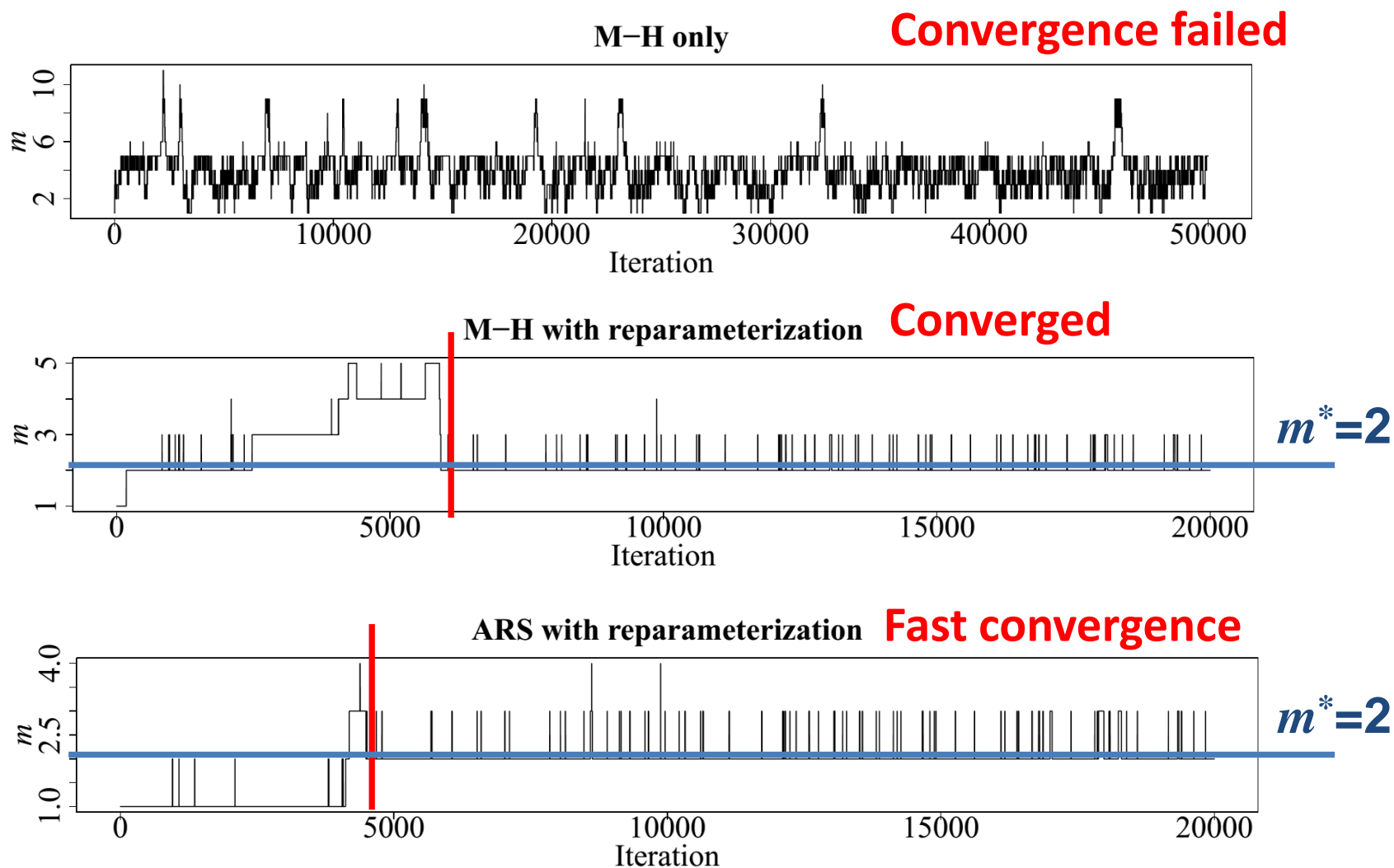


Figure 1. Model selection results

Table 1. Model estimation results

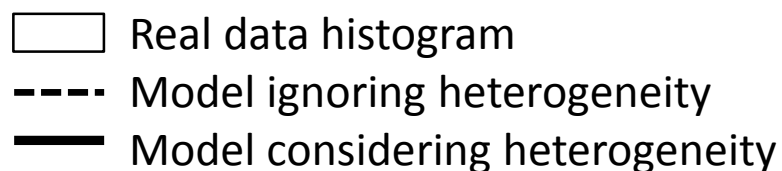
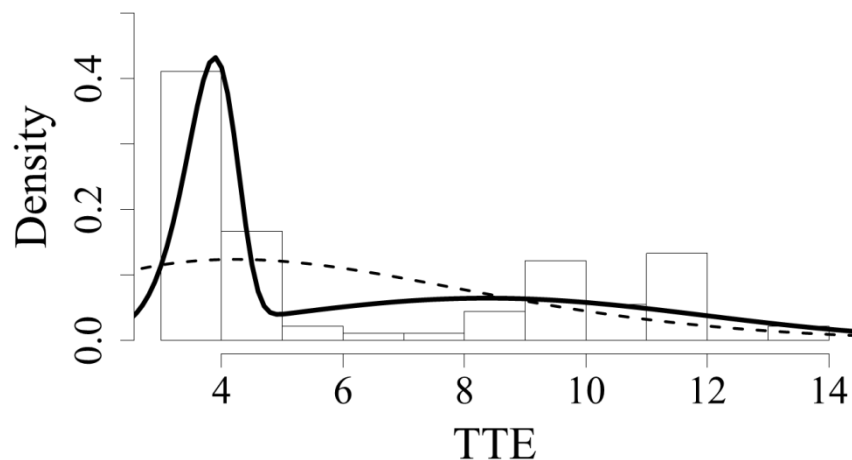
	Sub-population 1				Sub-population 2			
Parameter	p_1	k_1	η_1	β_1	p_2	k_2	η_2	β_2
True value	0.3	0.7	2.0e+3	1	0.7	3	8.0e+4	0.5
Estimate	0.28	0.66	1.95e+3	0.94	0.66	2.97	8.14e+4	0.51

Efficiency

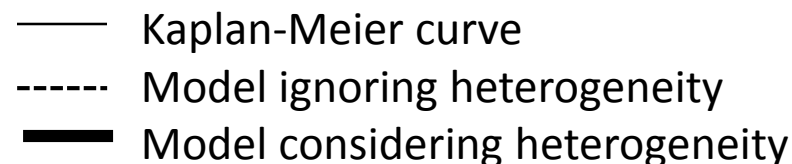
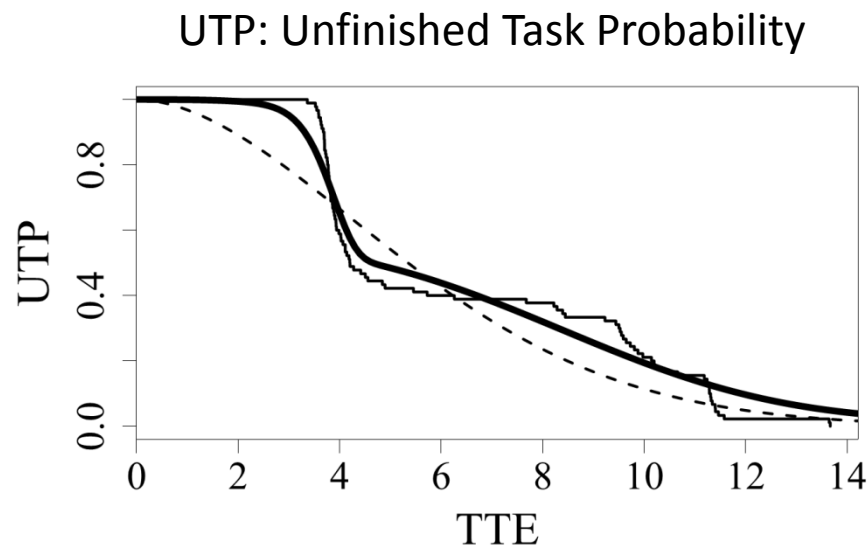


Real data analysis

- Assembly time data



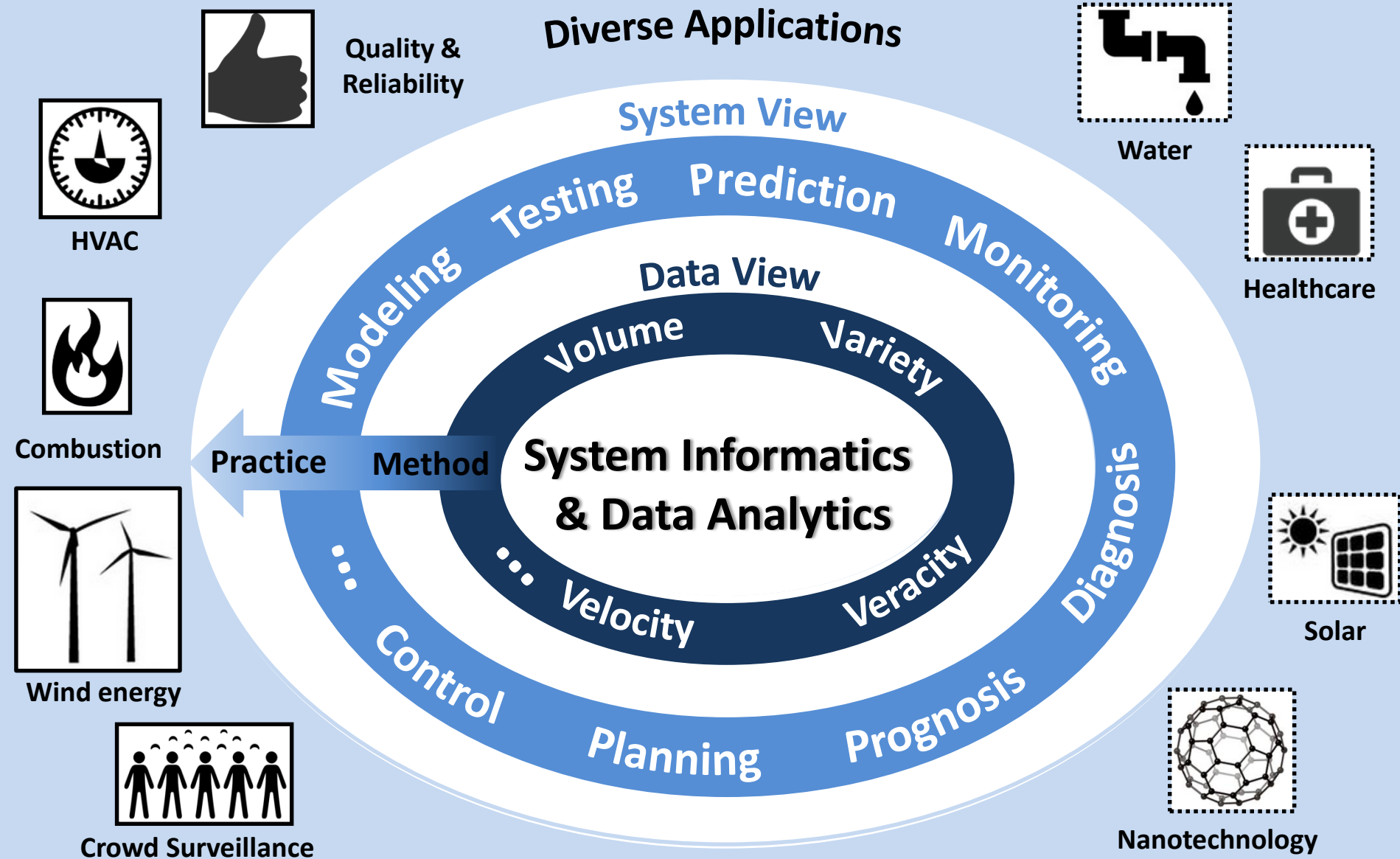
(a) Estimated densities comparison



(b) UTP curves comparison

Figure 4. Comparisons of models w/ and w/o considering heterogeneity

Summary



Thanks 😊

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